

Variant FCC Test Report

(PART 27)

Report No.: RF170301C11B

FCC ID: NM82PZC500

Test Model: 2PZC500

Received Date: May 05, 2017

Test Date: May 06, 2017 ~ May 08, 2017

Issued Date: May 19, 2017

Applicant: HTC Corporation

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Issued By: Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch

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Test Location (1): No. 19, Hwa Ya 2nd Rd, Wen Hwa Tsuen, Kwei Shan Hsiang, Taoyuan Hsien 333, Taiwan, R.O.C.



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Release Control Record

Issue No.	Description		Date Issued
RF170301C11B	Original Release		May 19, 2017



1 Certificate of Conformity

Product:	Smartphone
Brand:	HTC
Test Model:	2PZC500
Sample Status:	Production Unit
Applicant:	HTC Corporation
Test Date:	May 06, 2017 ~ May 08, 2017
Standards:	FCC Part 27, Subpart C, M

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

Prepared by :

Ivonne Wu / Supervisor

Date: May 19, 2017

Date:

May 19, 2017

Approved by :

David Huang / Project Engineer

Report No.: RF170301C11B Reference No.: 170505C44



	Applied Standard: FCC Part 27 & Part 2									
FCC Clause	Test Item	Result	Remarks							
2.1046 27.50(h)	Equivalent Isotropic Radiated Power	Pass	Meet the requirement of limit.							
2.1055 27.54 Frequency Stability		Pass	Meet the requirement of limit.							
2.1049 Occupied Bandwidth		Pass	Meet the requirement of limit.							
	Peak to Average Ratio		Meet the requirement of limit.							
2.1051 27.53(l)	Band Edge Measurements	Pass	Meet the requirement of limit.							
2.1051 27.53(m)	Conducted Spurious Emissions	Pass	Meet the requirement of limit.							
2.1053 27.53(m)	Radiated Spurious Emissions	Pass	Meet the requirement of limit. Minimum passing margin is -25.61 dB at 5340.2 MHz.							

2 Summary of Test Results

2.1 Measurement Uncertainty

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2:

Measurement	Frequency	Expended Uncertainty (k=2) (±)
Conducted Emissions at mains ports	150 kHz ~ 30 MHz	2.44 dB
Padiated Emissions up to 1 CHz	30 MHz ~ 200 MHz	2.0153 dB
Radiated Emissions up to 1 GHz	200 MHz ~1000 MHz	2.0224 dB
Radiated Emissions above 1 GHz	1 GHz ~ 18 GHz	1.0121 dB
	18 GHz ~ 40 GHz	1.1508 dB



2.2 Test Site and Instruments

Description & Manaufacturer	Model No.	Serial No.	Date of Calibration	Due Date of Calibration
Test Receiver Agilent	N9038A	MY51210203	Feb. 17, 2017	Feb. 16, 2018
Spectrum Analyzer Agilent	N9010A	MY52220314	Dec. 16, 2016	Dec. 15, 2017
Spectrum Analyzer ROHDE & SCHWARZ	FSU43	101261	Dec. 13, 2016	Dec. 12, 2017
BILOG Antenna SCHWARZBECK	VULB9168	9168-472	Dec. 26, 2016	Dec. 27, 2017
HORN Antenna SCHWARZBECK	BBHA 9120 D	9120D-969	Dec. 12, 2016	Dec. 13, 2017
Double Ridge Guide Horn Antenna EMCO	3115	5619	Dec. 26, 2016	Dec. 27, 2017
BILOG Antenna SCHWARZBECK	VULB 9168	9168-153	Dec. 12, 2016	Dec. 13, 2017
Fixed Attenuator Mini-Circuits	BW-N10W5+	NA	Jul. 08, 2016	Jul. 07, 2017
MXG Vector signal generator Agilent	N5182B	MY53050430	Oct. 19, 2016	Oct. 18, 2017
Preamplifier EMCI	EMC 012645	980115	Oct. 21, 2016	Oct. 20, 2017
Preamplifier EMCI	EMC 184045	980116	Oct. 21, 2016	Oct. 20, 2017
Preamplifier EMCI	EMC 330H	980112	Oct. 21, 2016	Oct. 20, 2017
Power Meter Anritsu	ML2495A	1232002	Sep. 08, 2016	Sep. 07, 2017
Power Sensor Anritsu	MA2411B	1207325	Sep. 08, 2016	Sep. 07, 2017
RF signal cable HUBER+SUHNNER	SUCOFLEX 104	309219/4 2950114	Oct. 21, 2016	Oct. 20, 2017
RF signal cable HUBER+SUHNNER	SUCOFLEX 104	250130/4	Oct. 21, 2016	Oct. 20, 2017
RF Coaxial Cable Worken	8D-FB	Cable-Ch10-01	Oct. 21, 2016	Oct. 20, 2017
Software BV ADT	E3 6.120103	NA	NA	NA
Antenna Tower MF	MFA-440H	NA	NA	NA
Turn Table MF	MFT-201SS	NA	NA	NA
Antenna Tower &Turn Table Controller MF	MF-7802	NA	NA	NA
Communications Tester-Wireless Agilent	8960 Series 10	MY53201073	Jul. 03, 2015	Jul. 02, 2017
Radio Communication Analyzer Anritsu	MT8820C	6201300640	Aug. 10, 2015	Aug. 09, 2017



- Note: 1. The calibration interval of the above test instruments is 12 / 24 months and the calibrations are traceable to NML/ROC and NIST/USA.
 - 2. The test was performed in HwaYa Chamber 10.
 - 3. The horn antenna and preamplifier (model: EMC 184045) are used only for the measurement of emission frequency above 1 GHz if tested.
 - 4. The FCC Site Registration No. is 690701.
 - 1. The IC Site Registration No. is IC7450F-10.



3 General Information

3.1 General Description of EUT

Product	Smartphone						
Brand	Smartphone HTC						
Test Model	HTC 2PZC500						
Status of EUT	2PZC500 Production Unit						
Status of EUT							
Dense Ormalia Define	5 Vdc or 9 Vdc or 12 Vdc (adapter)						
Power Supply Rating	5.0 Vdc (host equipment)						
	3.85 Vdc (Li-ion battery)						
Modulation Type	QPSK, 16QAM						
	LTE Band 41 (Channel Bandwidth: 20+20 MHz)	2506.0 ~ 2660.2 MHz					
	LTE Band 41 (Channel Bandwidth: 20+15 MHz)	2506.0 ~ 2662.9 MHz					
	LTE Band 41 (Channel Bandwidth: 20+10 MHz)	2506.0 ~ 2665.6 MHz					
	LTE Band 41 (Channel Bandwidth: 20+5 MHz)	2506.0 ~ 2668.3 MHz					
	LTE Band 41 (Channel Bandwidth: 15+20 MHz) 2503.5 ~ 2665.4 MHz						
Frequency Range	LTE Band 41 (Channel Bandwidth: 15+15 MHz)	2503.5 ~ 2667.5 MHz					
	LTE Band 41 (Channel Bandwidth: 15+10 MHz)	2503.5 ~ 2670.5 MHz					
	LTE Band 41 (Channel Bandwidth: 10+20 MHz)	2501.0 ~ 2670.6 MHz					
	LTE Band 41 (Channel Bandwidth: 10+15 MHz)	2501.0 ~ 2673.0 MHz					
	LTE Band 41 (Channel Bandwidth: 5+20 MHz)	2498.5 ~ 2675.8 MHz					
	LTE Band 41 (Channel Bandwidth: 20 MHz)	2506.0 ~ 2680.0 MHz					
Max. EIRP Power	LTE Band 41 (Channel Bandwidth: 20+20 MHz)	103.51 mW					
Emission Designator	LTE Band 41 (Channel Bandwidth: 20+20 MHz) 37M7G7D						
Antenna Type	Fixed Internal Antenna						
Accessory Device	Refer to Note as below						
Data Cable Supplied	Refer to Note as below						

Note:

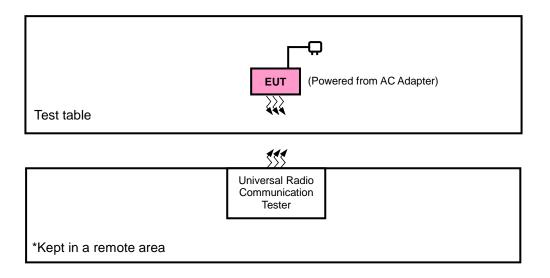
1. This report is issued as a supplementary report to BV CPS report no.: RF170301C11-10. The difference compared with original report is to enable LTE B41 CA function.

- 2. The EUT's accessories list refers to Ext. Pho.
- 3. The above EUT information is declared by manufacturer and for more detailed features description, please refer to the manufacturer's specifications or user's manual.



3.2 Configuration of System under Test

<Radiated Emission Test>



<E.I.R.P. Test>

Test table	EUT (Powered from battery)
	\$\$\$
	Universal Radio Communication Tester
*Kept in a remote area	

3.2.1 Description of Support Units

The EUT has been tested as an independent unit together with other necessary accessories or support units.



3.3 Test Mode Applicability and Tested Channel Detail

Pre-Scan has been conducted to determine the worst-case mode from all possible combinations between available modulations, data rates, XYZ axis, and antenna ports.

The worst case was found when positioned as the table below. Following channel(s) was (were) selected for the final test as listed below:

SIM	Band	EIRP	Radiated Emission
1	LTE Band 41	X-plane	Y-axis

LTE Band 41

EUT Configure Mode	Test Item	Available Channel	Tested Channel	Channel Bandwidth	Modulation
-	EIRP	39750 to 41490	39750, 40620, 41490	20+20 MHz	QPSK
-	Frequency Stability	39750 to 41490	39750, 41490	20+20 MHz	QPSK
-	Occupied Bandwidth	39750 to 41490	39750, 40620, 41490	20+20 MHz	QPSK
-	Peak to Average Ratio	39750 to 41490	39750, 40620, 41490	20+20 MHz	QPSK
-	Band Edge	39750 to 41490	39750, 41490	20+20 MHz	QPSK
-	Conducted Emission	39750 to 41490	39750, 40620, 41490	20+20 MHz	QPSK
-	Radiated Emission	39750 to 41490	39750, 40620, 41490	20+20 MHz	QPSK

Note: This device was tested under all bandwidths, RB configurations and modulations. The worst case was found in QPSK modulation.

Test Condition:

Test Item	Environmental Conditions	Input Power	Tested By
EIRP	25 deg. C, 65 % RH	3.85 Vdc	TobyTian
Frequency Stability	25 deg. C, 65 % RH	3.85 Vdc	Wayne Lin
Occupied Bandwidth	25 deg. C, 65 % RH	3.85 Vdc	Wayne Lin
Band Edge	25 deg. C, 65 % RH	3.85 Vdc	Wayne Lin
Peak to Average Ratio	25 deg. C, 65 % RH	3.85 Vdc	Wayne Lin
Condcudeted Emission	25 deg. C, 65 % RH	3.85 Vdc	Wayne Lin
Radiated Emission	25 deg. C, 65 % RH	120 Vac, 60 Hz	TobyTian



3.4 EUT Operating Conditions

The EUT makes a call to the communication simulator. The communication simulator station system controlled a EUT to export maximum output power under transmission mode and specific channel frequency

3.5 General Description of Applied Standards

The EUT is a RF Product. According to the specifications of the manufacturer, it must comply with the requirements of the following standards:

FCC 47 CFR Part 2 FCC 47 CFR Part 27 KDB 971168 D01 Power Meas License Digital Systems v02r02 ANSI/TIA/EIA-603-D 2010

Note: All test items have been performed and recorded as per the above standards.



4 Test Types and Results

4.1 Output Power Measurement

4.1.1 Limits of Output Power Measurement

The radiated peak output power shall be according to the specific rule Part 27.50(h)(2) that "User stations are limited to 2 watts" and 27.50(i) specific that "Peak transmit power must be measure over any interval of continuous transmission using instrumentation calibration in terms of rms-equivalent voltage."

4.1.2 Test Procedures

EIRP Measurement:

- a. All measurements were done at low, middle and high operational frequency range. RBW and VBW is 10 MHz for LTE mode.
- b. Substitution method is used for E.I.R.P measurement. In the semi-anechoic chamber, EUT placed on the 0.8 m height of Turn Table, rotated the table around 360 degrees to search the maximum radiation power and receiver antenna shall be rotated vertical and horizontal polarization and moved height from 1 m to 4 m to find the maximum polar radiated power. The "Read Value" is the spectrum reading the maximum power value.
- c. The substitution horn antenna is substituted for EUT at the same position and signals generator export the CW signal to the substitution antenna via a tx cable. Rotated the Turn Table and moved receiving antenna to find the maximum radiation power. Adjust output power level of S.G to get a Value of spectrum reading equal to "Read Value" of step b. Record the power level of S.G.
- d. EIRP = Output power level of S.G TX cable loss + Antenna gain of substitution horn.

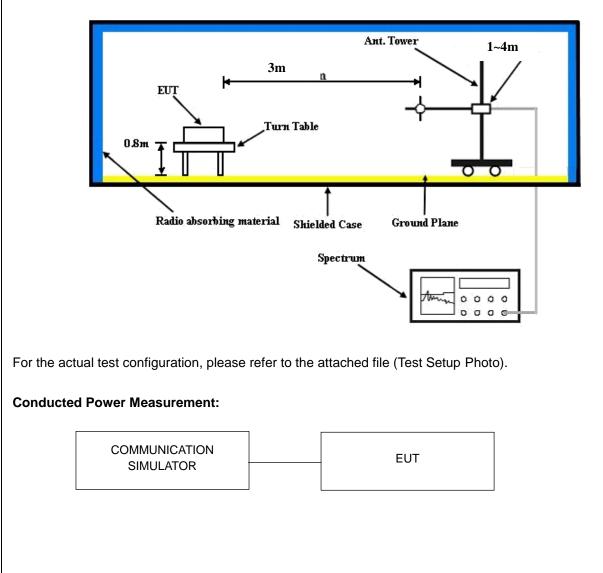
Conducted Power Measurement:

- a. The EUT was set up for the maximum power with LTE link data modulation and link up with simulator.
- b. Set the EUT to transmit under low, middle and high channel and record the power level shown on simulator.



4.1.3 Test Setup

EIRP / ERP Measurement:





4.1.4 Test Results

Conducted Output Power (dBm)

< CA uplink >

	Co	onducted Po	ower Mea	surement	for LTE-C	A (Carrier	Aggregatio	on)_ Intra-	-Band Co	ntiguous (2CC)															
	PCC (Prin	nary Compon	ent Carrier)	S	CC (Second	dary Compon	ent Carrie	r)	Tx Power	Tx Power With UL-CA														
LTE Band	BW (MHz)	Uplink Channel	RB Size	RB Offset	LTE Band	BW (MHz)	Uplink Channel	RB Size	RB Offset	Without UL-CA Active	Active for Total power														
		39750					39948			24.95	24.17														
41	20	40620	100	0	41	20	40818	100	0	24.92	24.51														
		41490					41292			24.01	24.41														
		39750					39921			24.95	22.26														
41	20	40620	100	0	41	15	40791	75	0	24.92	22.03														
		41490					41319			24.01	22.29														
		39750					39894			24.95	22.47														
41	20	40620	100	0	41	10	40764	50	0	24.92	22.81														
		41490					41346			24.01	22.46														
		39750					39867			24.95	22.29														
41	20	40620	100	0	41	5	40737	25	0	24.92	22.85														
		41490					41373			24.01	22.37														
	15	39725		0	41	20 4079	39896			24.81	22.43														
41		40620	75				40791	100	0	24.78	22.98														
		41515					41344			23.86	22.51														
		39725			0 41	15	39875			24.81	22.56														
41	15	40620	75	0			40770	75	0	24.78	22.83														
		41515					41365			23.86	22.50														
		39725			41		39845			24.81	22.35														
41	15	40620	75	0		41	41	41	41	41	41	41	41	41	41	41	10	40740 50	50	50	50	50 0	50 0	0	24.78
		41515					41395			23.86	22.42														
		39700					39844			24.71	22.96														
41	10	40620	50	0	41	20	40764	100	0	24.68	22.72														
		41540					41396			23.71	22.43														
		39700					39820			24.71	23.27														
41	10	40620	50	0	41	15	40740	75	0	24.68	24.75														
		41540					41420			23.71	23.93														
		39675					39792			24.56	22.35														
41	5	40620	25	0	41	20	40737	100	0	24.54	22.85														
		41565					41448			23.56	22.22														



EIRP Power (dBm)

				LTE Band 41			
		CI	hannel Band	dwidth: 20+20 M	Hz / QPSK		
Plane	Channel	Frequency (MHz)			EIRP (dBm)	EIRP (mW)	Polarization (H/V)
	39750	2515.9	-19.15	39.26	20.11	102.57	
	40620	2602.9	-18.02	38.17	20.15	103.51	Н
v	41490	2670.1	-18.62	38.71	20.09	102.09	
X	39750	2515.9	-25.55	39.33	13.78	23.88	
	40620	2602.9	-24.81	38.68	13.87	24.38	V
	41490	2670.1	-24.91	38.76	13.85	24.27	
		Ch	annel Band	width: 20+20 MH	lz / 16QAM		
	39750	2515.9	-20.23	39.26	19.03	79.98	
	40620	2602.9	-18.96	38.17	19.21	83.37	Н
V	41490	2670.1	-19.63	38.71	19.08	80.91	
Х	39750	2515.9	-27.26	39.33	12.07	16.11	
	40620	2602.9	-26.58	38.68	12.10	16.22	V
	41490	2670.1	-26.71	38.76	12.05	16.03	



4.2 Frequency Stability Measurement

4.2.1 Limits of Frequency Stabiliity Measurement

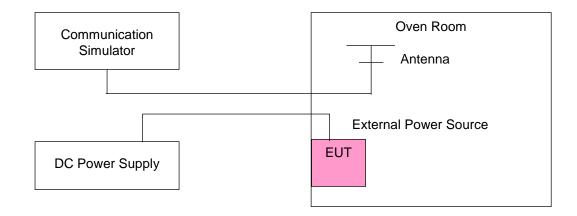
The frequency stability shall be sufficient to ensure that the fundamental emissions stay within the authorized bands of operation.

4.2.2 Test Procedure

- a. Device is placed at the oven room. The oven room could control the temperatures and humidity. Power warm up is at least 15 min and power applied should perform before recording frequency error.
- b. EUT is connected the external power supply to control the DC input power. The test voltage range is from minimum to maximum working voltage. Each step shall be record the frequency error rate.
- c. The temperature range step is 10 degrees in this test items. All temperature levels shall be hold the ± 0.5 °C during the measurement testing. The each temperature step shall be at least 0.5 hours, consider the EUT could be test under the stability condition.

NOTE: The frequency error was recorded frequency error from the communication simulator.

4.2.3 Test Setup





4.2.4 Test Results

Frequency Error vs. Voltage

Voltage					
(Volts)	Low C	hannel	High C	Limit (ppm)	
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)	
3.85	2515.900004	0.0016	2670.100003	0.0009	2.5
3.6	2515.900001	0.0005	2670.100002	0.0006	2.5
4.4	2515.900003	0.0011	2670.100002	0.0008	2.5

Note: The applicant defined the normal working voltage of the battery is from 3.6 Vdc to 4.4 Vdc.

Frequency Error vs. Temperature

		LTE B	and 41					
		Channel Bandw	idth: 20+20 MHz					
Temp. (℃)	Low C	hannel	High C	High Channel				
	Frequency (MHz)	Frequency Error (ppm)	Frequency (MHz)	Frequency Error (ppm)				
-30	2515.900004 0.0014		2670.100004	0.0014	2.5			
-20	2515.900003	0.0012	2670.100004	0.0014	2.5			
-10	2515.900001	0.0005	2670.100003	0.0011	2.5			
0	2515.900003	0.0011	2670.100002	0.0007	2.5			
10	2515.900003	0.0011	2670.100003	0.0012	2.5			
20	2515.899999	-0.0005	2670.099998	-0.0008	2.5			
30	2515.899997	-0.0012	2670.099997	-0.0010	2.5			
40	2515.899997	-0.0013	2670.099999	-0.0005	2.5			
50	2515.899997	-0.0012	2670.099997	-0.0012	2.5			
55	2515.899997	-0.0011	2670.099999	-0.0004	2.5			



4.3 Occupied Bandwidth Measurement

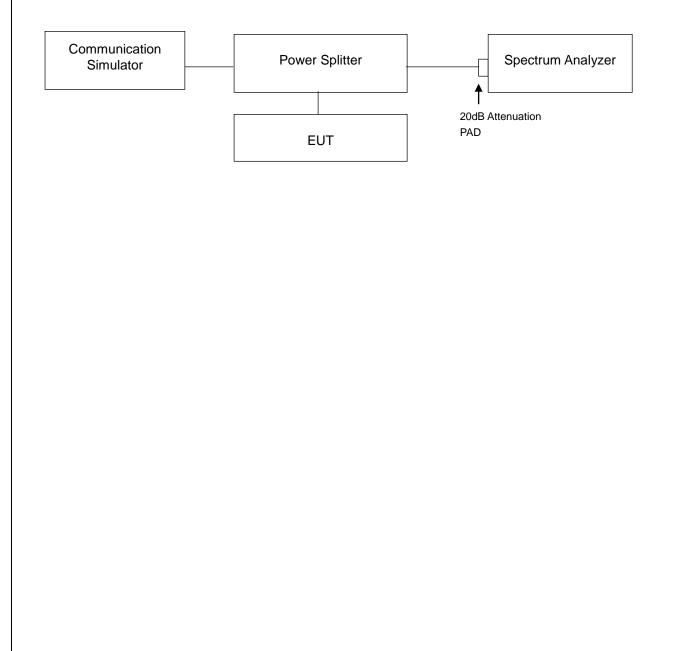
4.3.1 Limits of Occupied Bandwidth Measurement

The width of a frequency band such that, below the lower and above the upper frequency limits, the mean powers emitted are each equal to a specified percentage 0.5 % of the total mean power of a given emission.

4.3.2 Test Procedure

- a. The conducted occupied bandwidth used the power splitter via EUT RF power connector between simulation base station and spectrum analyzer.
- b. Use OBW measurement function of Spectrum analyzer to measure 99 % occupied bandwidth.

4.3.3 Test Setup





4.3.4 Test Result

LTE Band 41								
Channel Bandwidth: 20+20 MHz								
Channel Frequency 99 % Occupied (MHz) Bandwidth (MHz)								
39750 & 39948	2515.9	37.7050						
40620 & 40818	2602.9	37.6770						
41490 & 41292	2670.1	37.6880						

enter Fr	RF 50 Ω DC eq 2.515900000	GHz Center Trig: F	SENSE:INT AL Freq: 2.515900000 GHz free Run Avg[Hold:>1 : 30 dB	IGN AUTO [06:07:33 PM May 06, 2017 Radio Std: None 1/1 Radio Device: BTS	Frequency
0 dB/div	Ref Offset 15 dB Ref 35.00 dBm	1			
og 25.0 15.0 5.00 5.00 15.0 15					Center Fre 2.515900000 GH
enter 2.5 Res BW		#	VBW 3 MHz	Span 80 MHz #Sweep 81 ms	
Occup	ied Bandwidtl 37	705 MHz	Total Power	23.8 dBm	Auto Mai
	iit Freq Error andwidth	-45.750 kHz 39.72 MHz	% of OBW Power x dB	99.00 % -26.00 dB	он

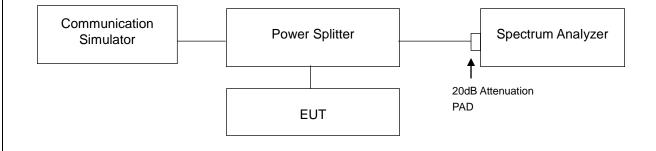


4.4 Band Edge Measurement

4.4.1 Limits of Band Edge Measurement

According to FCC 27.53(I)(4) specified that power of any emission outside of the channel edge must be attenuated below the transmitting power (P) by a factor shall be not less than 40 + 10 log (P) dB on all frequencies between the channel edge and 5 megahertz from the channel edge, 43 + 10 log (P) dB on all frequencies between 5 megahertz and X megahertz from the channel edge, and 55 + 10 log (P) dB on all frequencies more than X megahertz from the channel edge, where X is the greater of 6 megahertz or the actual emission bandwidth. In addition, the attenuation factor shall not be less that 43 + 10 log (P) dB on all frequencies between 2490.5 MHz and 2496 MHz and 55 + 10 log (P) dB at or below 2490.5 MHz. In the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least two percent may be employed, except when the 1 megahertz band is 2495-2496 MHz, in which case a resolution bandwidth of at least one percent may be employed.

4.4.2 Test Setup

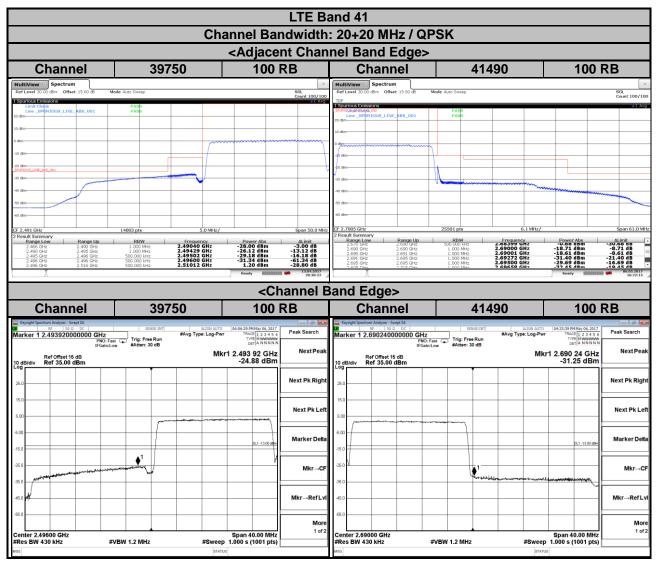


4.4.3 Test Procedures

- a. The EUT was set up for the maximum peak power with LTE link data modulation. The power was measured with R&S Spectrum Analyzer. All measurements were done at 2 channels (low and high operational frequency range.).
- b. The band edge measurement used the power splitter via EUT RF power connector between simulation base station and spectrum analyzer.
- c. The center frequency of spectrum is the band edge frequency and span is 80 MHz. RB of the spectrum is 200 kHz and VB of the spectrum is 1 MHz (Channel bandwidth 20 MHz).
- d. Record the max trace plot into the test report.



4.4.4 Test Results



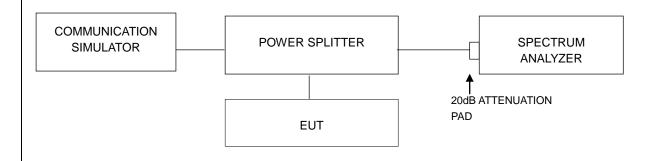


4.5 Peak to Average Ratio

4.5.1 Limits of Peak to Average Ratio Measurement

In measuring transmissions in this band using an average power technique, the peak to-average ratio (PAR) of the transmission may not exceed 13 dB.

4.5.2 Test Setup



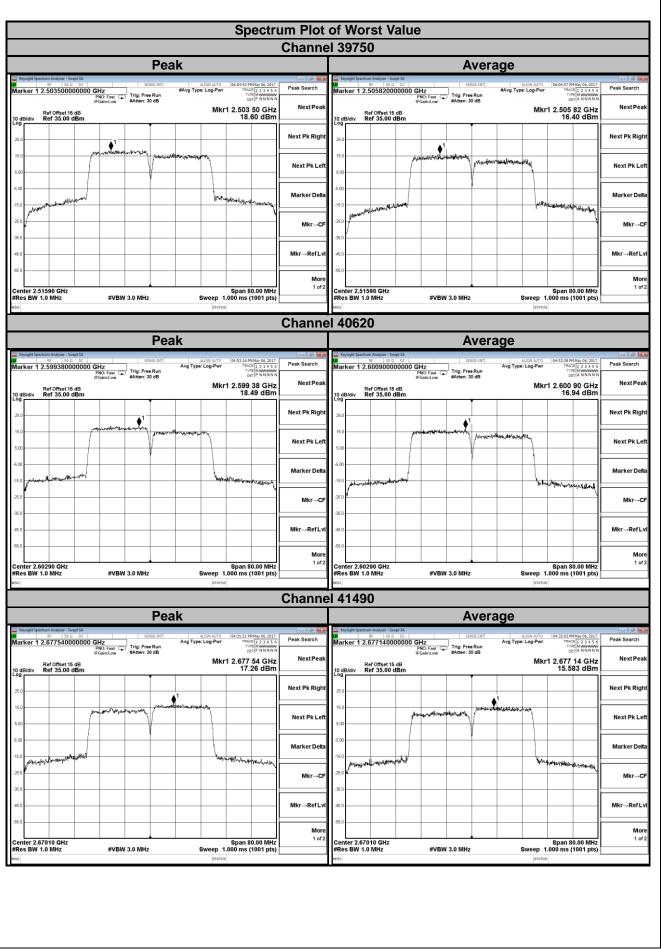
4.5.3 Test Procedures

- 1. Set resolution/measurement bandwidth ≥ signal's occupied bandwidth;
- 2. Set the number of counts to a value that stabilizes the measured CCDF curve;
- 3. Record the maximum PAPR level associated with a probability of 0.1 %.

4.5.4 Test Results

	LTE Band 41									
Channel Bandwidth: 20+20 MHz										
Channel	Frequency (MHz)	Peak to Average Ratio (dB)								
39750 & 39948	2515.9	2.20								
40620 & 40818	2602.9	1.55								
41490 & 41292	2670.1	1.68								





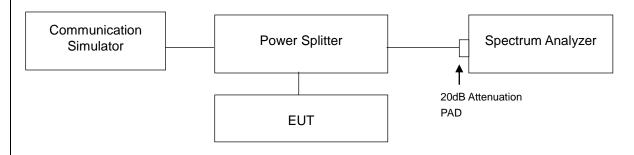


4.6 Conducted Spurious Emissions

4.6.1 Limits of Conducted Spurious Emissions Measurement

The power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) by at least 55 +10 log10(P) dB. The limit of emission is equal to -25 dBm.

4.6.2 Test Setup

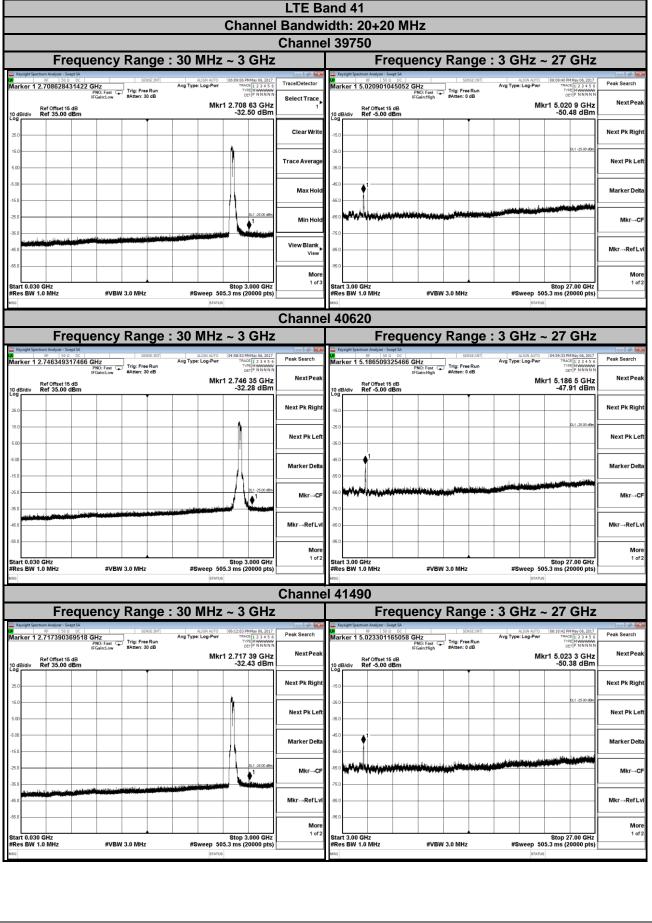


4.6.3 Test Procedure

- a. The EUT makes a phone call to the communication simulator. All measurements were done at low, middle and high operational frequency range.
- b. Measuring frequency range is from 30 MHz to 27 GHz for LTE Band 41. 10dB attenuation pad is connected with spectrum. RBW=1MHz and VBW=3MHz are used for conducted emission measurement.



4.6.4 Test Results





4.7 Radiated Emission Measurement

4.7.1 Limits of Radiated Emission Measurement

The power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) by at least 55 +10 log10(P) dB. The limit of emission is equal to -25 dBm.

4.7.2 Test Procedure

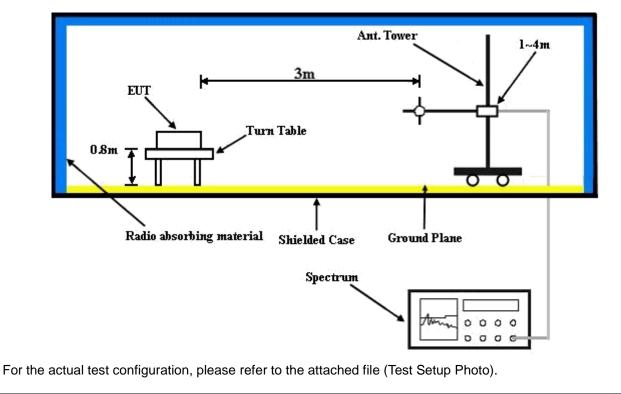
- a. Substitution method is used for E.I.R.P measurement. In the semi-anechoic chamber, EUT placed on the 0.8 m height of Turn Table, rotated the table around 360 degrees to search the maximum radiation power and receiver antenna shall be rotated vertical and horizontal polarization and moved height from 1 m to 4 m to find the maximum polar radiated power. The "Read Value" is the spectrum reading the maximum power value.
- b. The substitution horn antenna is substituted for EUT at the same position and signals generator export the CW signal to the substitution antenna via a TX cable. Rotated the Turn Table and moved receiving antenna to find the maximum radiation power. Adjust output power level of S.G to get a Value of spectrum reading equal to "Read Value" of step a. Record the power level of S.G.
- c. EIRP = Output power level of S.G TX cable loss + Antenna gain of substitution horn.
- d. E.R.P power can be calculated form E.I.R.P power by subtracting the gain of dipole, E.R.P power = E.I.P.R power 2.15 dBi.

NOTE: The resolution bandwidth of spectrum analyzer is 1 MHz and the video bandwidth is 3 MHz.

4.7.3 Deviation from Test Standard

No deviation.

4.7.4 Test Setup





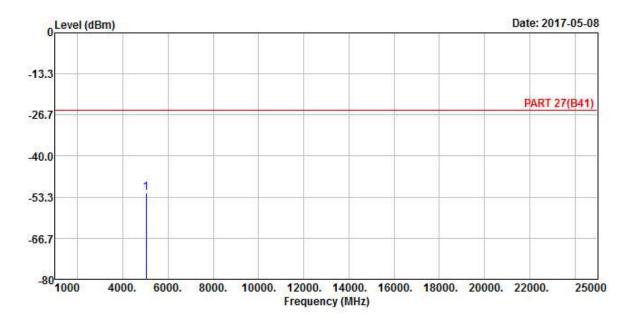
4.7.5 Test Results

LTE Band 41

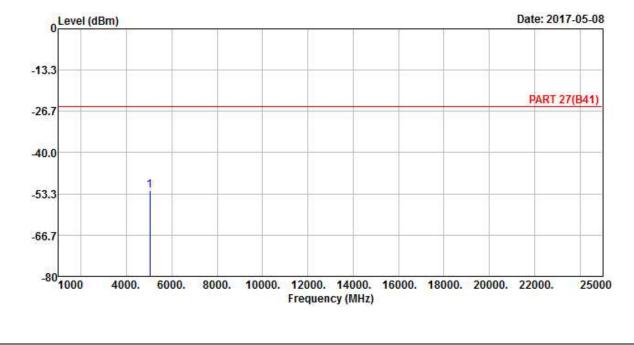
Channel Bandwidth: 20+20 MHz / QPSK

Low Channel

Frequency (MHz)	ERP(dBm)	Limit(dBm)	Over Limit (dB)	SPA. Reading (dBm)	S.G. Power (dBm)	TX Cable loss (dB)	TX Antenna Gain (dBi)	Polarization (H/V)	Result
5031.8	-51.96	-25	-26.96	-48.70	-56.89	5.7	10.63	Н	Pass



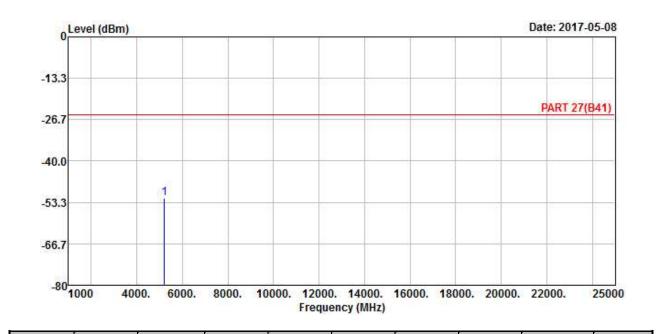
Frequency (MHz)	ERP(dBm)	Limit(dBm)	Over Limit (dB)	SPA. Reading (dBm)	S.G. Power (dBm)	TX Cable loss (dB)	TX Antenna Gain (dBi)	Polarization (H/V)	Result
5031.8	-52.15	-25	-27.15	-48.89	-57.08	5.7	10.63	V	Pass



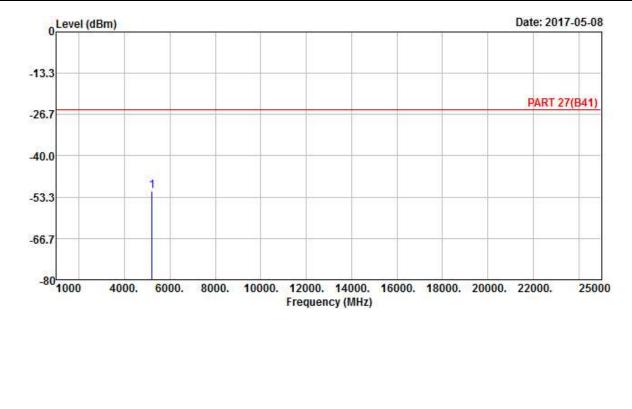


Middle Channel

Frequency (MHz)	ERP(dBm)	Limit(dBm)	Over Limit (dB)	SPA. Reading (dBm)	S.G. Power (dBm)	TX Cable loss (dB)	TX Antenna Gain (dBi)	Polarization (H/V)	Result
5205.8	-51.97	-25	-26.97	-49.34	-57.10	5.72	10.85	Н	Pass



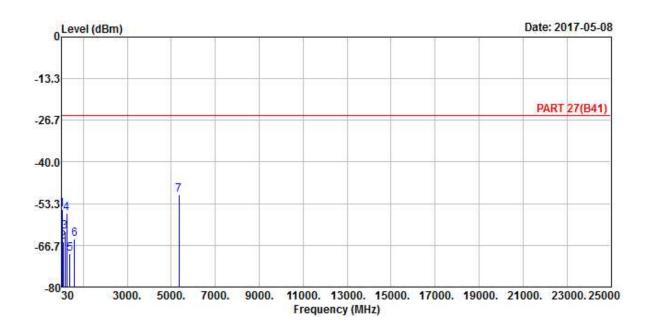
Frequency (MHz)	ERP(dBm)	Limit(dBm)	Over Limit (dB)	SPA. Reading (dBm)	S.G. Power (dBm)	TX Cable loss (dB)	TX Antenna Gain (dBi)	Polarization (H/V)	Result
5205.8	-51.44	-25	-26.44	-48.81	-56.57	5.72	10.85	V	Pass



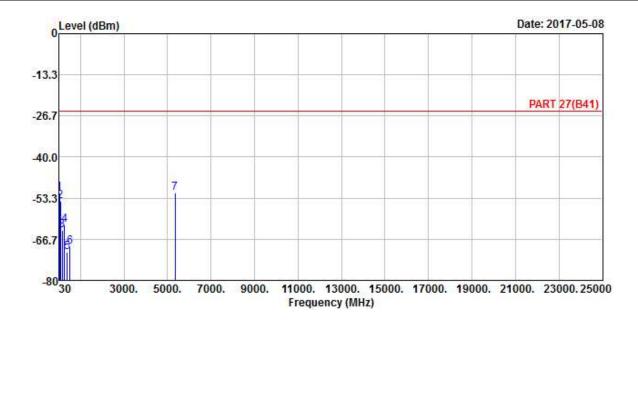


High Channel

Frequency (MHz)	ERP(dBm)	Limit(dBm)	Over Limit (dB)	SPA. Reading (dBm)	S.G. Power (dBm)	TX Cable loss (dB)	TX Antenna Gain (dBi)	Polarization (H/V)	Result
5340.2	-50.61	-25	-25.61	-49.59	-55.69	5.74	10.82	Н	Pass



Frequency (MHz)	ERP(dBm)	Limit(dBm)	Over Limit (dB)	SPA. Reading (dBm)	S.G. Power (dBm)	TX Cable loss (dB)	TX Antenna Gain (dBi)	Polarization (H/V)	Result
5340.2	-51.61	-25	-26.61	-49.59	-56.69	5.74	10.82	V	Pass





5 Pictures of Test Arrangements

Please refer to the attached file (Test Setup Photo).



Appendix – Information on the Testing Laboratories

We, Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch, were founded in 1988 to provide our best service in EMC, Radio, Telecom and Safety consultation. Our laboratories are accredited and approved according to ISO/IEC 17025.

If you have any comments, please feel free to contact us at the following:

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The address and road map of all our labs can be found in our web site also.

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